

Linear transformed control charts for short–run or long–run processes*

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Abstract

We propose linear transformed short run control charts for the process mean and variance. They can be used from the start of production. The control limits are plus and minus 3 and the center line is 0. Moreover, the type I risk of the proposed charts equals the conventional value 0.27%. We compare the type I and type II risks among our control chart and existing short run charts are given.

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